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15	DISTRIBUTING
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5 6	FREQUENCYS
27	INTENSITIES
28	INTENSITY
29	INTENSITYS
30	OSCILLOSCOPE
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32	POWER
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	Search Terms
34	RATE
35	RATES
36	SAMPLE
37	SAMPLED
38	SAMPLEDS
39	SAMPLER
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43	5584							
44	2737782							
45	479213							
46	125							

	Current XRef	Retrieval Classif	Inventor	S	v	۵	2 3	4	S	Image Doc. Displayed	PT
Ħ.	438/82		Bazan, Guillermo C. et al.	_×_						US 20050035346	•
7			Mahoney, Leonard J. et al.							US 20050011611	
ო_			Martin, Andrew Louis							US 20040252586	
4	356/28.5		Ortyn, William E. et al.						,	US 20040223135	
2			Shattil, Steve J.							US 20040213351	
9	324/247		Butters, Bennett M. et al.							US 20040183530	
_	204/298.03; 204/298.06		Buda, Paul R.							US 20040182697	
8	•		Jupp, David L et al.							US 20040130702	
6			Kelly, Craig A.							US 20040087865	
10	435/252.3; 435/254.2		Short, Jay M.							US 20040077090	
11	385/117		Dong Yang, Victor Xiao et al.						_	US 20040076390	
12	702/87; 73/866.5		Degertekin, F. Levent et al.							US 20040020279	
13	345/519; 345/545		Deering, Michael F. et al.							US 20040012600	
14			Leslie, Brian C. et al.							US 20030227619	
15			Leslie, Brian C. et al.							US 20030206294	
16	204/192.12; 204/298.03; 204/298.06; 204/298.08		Buda, Paul R.					,		US 20030205460	
17			Karellas, Andrew et al.							US 20030169847	
18	428/1.1		Boden, Neville et al.							US 20030160212	

	Current XRef	Retrieval Classif	Inventor	s	၁	۵,	2	€.	4.	2	Image Doc. Displayed	ΡŢ
19	356/28.5		Ortyn, William E. et al.								US 20030142289	
50			LaDue, Christoph							_ر	US 20030133423	
21			Fala, Joseph M. et al.								US 20030048500	
22		,	Vander Jagt, Peter G. et al.					-			US 20030048449	
23	73/105		Degertekin, F. Levent et al.								JS 20030041669	_
24			Degertekin, F. Levent								US 20030041657	
25	369/112.24; 369/52.1; 369/53.22		Worthington, Mark Oscar							رد	US 20030035352	
56	96/209		Handy, Erik S. et al.									
27			Worthington, Mark Oscar et al.									
28			Gillispie, Gregory									
29	369/59.11		Powelson, Judith C. et al.									
30			Riley, James K. et al.									
31			Velazquez, Scott R.									
32			Ortyn, William E. et al.									
33			Shattil, Steve J.									
34	426/581; 426/601; 426/602		Arends, Berend Jan et al.									

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	>	H	Document ID	Issue Date	Pages	Title	Current OR
35	×		US 20010033238 A1	20011025		Linearity error compensator	341/118
36	×		US 6888633 B2	20050503		Color measurement instrument with modulated illumination	356/407
37	×		US 6888627 B2	20050503		Optical scanning system for surface inspection	356/237.2
38	×	,	US 6879817 B1	20050412		DC offset, re-radiation, and I/Q solutions using universal frequency translation technology	455/296
39	_×_		US 6873836 B1	20050329		Universal platform module and methods and apparatuses relating thereto enabled by universal frequency translation technology	455/313
40	×		US 6836650 B2	20041228		Methods and systems for down-converting electromagnetic signals, and applications thereof	455/319
14	×_		US 6813485 B2	20041102		Method and system for down-converting and up- converting an electromagnetic signal, and transforms for same	455/313
42	 ×		US 6798351 B1	20040928		Automated meter reader applications of universal frequency translation	340/870.02
43	×		US 6779387 B2	20040824		Method and apparatus for the ultrasonic actuation of the cantilever of a probe-based instrument	73/105
44	×		US 6778263 B2	20040817		Methods of calibrating an imaging system using calibration beads	356/28
45	_×		US 6736944 B2	20040518	_	Apparatus and method for arc detection	204/192.13
46	×		US 6704558 B1	20040309		Image-reject down-converter and embodiments thereof, such as the family radio service	455/323
47	×		US 6704549 B1	20040309		Multi-mode, multi-band communication system	455/102
48	_×_		US 6694817 B2	20040224		Method and apparatus for the ultrasonic actuation of the cantilever of a probe-based instrument	73/661

Current XRef Retireval Classif Inventor S C P 2 3 4 5 Image Doc. 250/226 Melazquez, Scott R. 1 <td< th=""></td<>
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	Current XRef	Retrieval Classif	Inventor	v	v	۵	7	٣	7	Image Doc. Displayed	
64	327/105; 331/143; 331/34; 376/376; 455/260	,	Sorrells; David F. et al.		•	·					
20	252/299.01; 252/299.61; 252/299.62; 532/1; 544/343; 546/70; 568/632;		Boden; Neville et al.							·	
21	455/313; 455/333		Sorrells; David F. et al.								
52			Shattil; Steve J.								
23	455/61		Bultman; Michael J. et al.								
54	426/239; 426/495; 426/524; 426/601		Arends; Berend Jan et al.								
55	329/362; 329/369; 455/313		Sorrells; David F. et al.								
56	345/440.1		Gauland; Michael A. et al.								
57	341/120		Velazquez; Scott R.								
. 85	375/328; 375/351		Cook; Robert W. et al.								

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59	375/219; 455/113; 455/83		Sorrells; David F. et al.									
09	356/28.5; 356/39		Ortyn; William E. et al.	·								
61	702/42		Radomski; James V.									
62	356/28.5; 356/39		Riley; James K. et al.									
63	381/84; 381/94.1		Jackson; Douglas L.			-						
64	348/445; 348/446; 348/458; 348/556		Stapleton; John J.									
9			Krahn; John Raymond et al.							•		
99	341/120		Velazquez; Scott R.									
	455/323; 455/333		Cook; Robert W. et al.									
89	250/584; 250/585; 250/586; 250/591; 356/417; 359/216		Basiji; David A. et al.									
69	327/113; 455/313		Sorrells; David F. et al.						-			
, 0/	455/115.1	-	Sorrells; David F. et al.									
71	341/120		Velazquez; Scott R.									
72	455/113		Sorrells; David F. et al.					•				

	Current XRef	Retrieval Classif	Inventor	S	C	Ь	2	3	4	2	Image Doc. Displayed	ь
73	607/50; 607/73		Bianco; Bruno et al.									
	250/458.1; 250/585; 250/586;											~
74	336/417; 359/201; 359/208; 359/208;		Basiji; David A. et al.				•			•		
75	341/120		Velazquez; Scott R.					-				
76	348/445; 348/446; 348/458;		Stapleton; John J.					<u> </u>				
	327/103; 375/350; 455/115.1		Sorrells; David F. et al.									
78			Leslie; Brian C. et al.									
79	370/497; 375/296; 455/102		Bultman; Michael J. et al.									
80	455/313; 455/323; 455/324		Sorrells; David F. et al.			•						
81	455/296		Cook; Robert W. et al.									
82	704/205; 704/206; 704/207		Holzrichter; John F.									
83	324/121R; 324/130; 324/379		Frankovitch, Jr.; Ed et al.									
84			Rushbrooke; John Gordon et al.									

Kapian, Richard Frederic et al. Bianco; Bruno et al. Fammer; Brian W. Fammer; Brian W. Kuhr; Werner G. et al. Kuhr; Werner G. et al. Williams; Donald V. et al. Correa, Paulo N. et al. D2; Wernikoff; Robert E. Hyart; Gilbert P. Kinna, Vikram K. Widdenshoven; Franciscus P. et al. Widdenshoven; Franciscus P. et al.		Current XRef	Retrieval Classif	Inventor	S	၁	a.	2	3	4	2	Image Doc. Displayed	Ы
Bianco; Bruno et al. Farmer; Brian W. Ming; Hao et al.	600/26; 600/300; 600/545			Kaplan; Richard Frederic et al.									
Farmer; Brian W. Ying; Hao et al. Kuhr; Werner G. et al. Williams; Donald V. et al. Bradley; Donald A. et al. Correa; Paulo N. et al. Wernikoff; Robert E. Barrett; Terence W. Hyatt; Gilbert P. Kinra; Wikdam K. Widdershoven; Franciscus P. et al.	600/408; 600/547			Bianco; Bruno et al.						<i>'</i>			
Kuhr; Werner G. et al. Williams; Donald V. et al. Bradley; Donald A. et al. Correa; Paulo N. et al. Wernikoff; Robert E. Barrett; Terence W. Kinna; Vikram K. Widdershoven; Franciscus P. et al.	356/28.5			Farmer; Brian W.	*								
Kuhr; Werner G. et al. Williams; Donald V. et al. Bradley; Donald A. et al. Correa; Paulo N. et al. Wernikoff; Robert E. Barrett; Terence W. Hyatt; Gilbert P. Kirra; Vikram K. Widdershoven; Franciscus P. et al. Widdershoven; Franciscus P. et al.	601/2			Ying; Hao et al.	·								
Williams; Donald V. et al. Bradley; Donald A. et al. Correa; Paulo N. et al. Wernikoff, Robert E. Barrett; Terence W. Hyatt; Gilbert P. Kinra; Vikram K. Widdershoven; Franciscus P. et al.	204/400; 204/434; 205/794			Kuhr; Werner G. et al.									
Bradley; Donald A. et al.	345/440; 706/920			Williams; Donald V. et al.	_				_				
Correa; Paulo N. et al. Wernikoff; Robert E.	324/601			Bradley; Donald A. et al.									
Wernikoff, Robert E. Barrett; Terence W. Hyatt; Gilbert P. Kinra; Vikram K. Widdershoven; Franciscus P. et al.	315/339; 315/349	,		Correa; Paulo N. et al.					_				
Barrett; Terence W. Hyatt; Gilbert P. Kinra; Vikram K. Widdershoven; Franciscus P. et al.	250/363.02; 250/370.1; 250/371		-	Wernikoff; Robert E.									
. Hyatt; Gilbert P. Kinra; Vikram K. Widdershoven; Franciscus P. et al.	342/21; 342/22; 342/83			Barrett; Terence W.									
Kinra; Vikram K. Widdershoven; Franciscus P. et al.	382/263; 708/300			Hyatt; Gilbert P.									
Widdershoven; Franciscus P. et al.	73/602			Kinra; Vikram K.		.,							
	257/254; 257/416; 377/62			Widdershoven; Franciscus P. et al.							-		

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110	702/17; 708/307; 708/422	:	Hyatt; Gilbert P.									
111			Hyatt; Gilbert P.								•	
112	708/423		Hyatt; Gilbert P.									
113			Hyatt; Gilbert P.									
114	386/125; 386/94		Knight; Howard W. et al.					-				
115	356/432		Patel; Chandra K. N. et al.									
116	360/22; 360/63; 360/78.04; 386/92	·	Diermann; Joachim P. et al.									
117	600/447; 600/455; 73/602; 73/861.25		Papadofrangakis; Emmanuel et al.									
118			Hyatt; Gilbert P.									
119	244/3.16; 250/203.1; 250/332; 250/342; 250/347; 250/349; 356/141.4;		Watkins; Robert A.			·						
120	600/441; 600/455; 73/641		Papadofrangakis; Emmanuel et al.			·						
121			Gallo; Luigi C.					-				
122	367/7		Green; Philip S. et al.								•	

Document ID Issue Date	Issue Date	 Pages	Title	Current OR
US 3896266 A 19750722	19750722	J 6	Credit and other security cards and card utilization systems therefore	379/114.19
JS 3515981 A 19700602	19700602	<u>15</u> 15	Super-regenerative resonance Spectrometers	324/310
US 3475680 A 19691028	19691028	<u>af</u>	IMPULSE RESONANCE SPECTROMETER INCLUDING A TIME AVERAGING COMPUTER AND FOURIER	324/312

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123	379/91.01; 379/93.03; 902/22; 902/23; 902/3		Waterbury; Nelson J.									
124			TONG DAVID ARTHUR et al.									
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